

**Notice of References Cited**

Application/Control No.

09/840,629

Applicant(s)/Patent Under  
Reexamination  
TROBAUGH ET AL.

Examiner

Ryan J. Miller

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Trobaugh et al., "A Physically Based, Probabilistic Model for Ultrasonic Images Incorporating Shape, Microstructure, and System Characteristics", IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, Nov. 2001, Vol. 48, pp. 1594-1605.
	V	Trobaugh et al., "A Discrete-Scatterer Model for Ultrasonic Images of Rough Surfaces", IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, Nov. 2000, Vol. 47, pp. 1520-1529.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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